| Add figure 4. Change transition times and propagation delay times in table 1. Change terminal connections. Add subgroup 8 in table 11. Change terminal connections. A | | | | | | | | | | | | RE | VISI | ONS | ; | | | | | | | | _ | | | | |
|--|---------|------------------------|-----------------|-----------------|-------------------|-----------|--------------------|--------------------|-------------------|--------------------|----------------------|----------------------|----------|-------------|---------|-------------|-----|------|------|------|----------|-------|----------|-----------|------|------|----------|
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| FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE 22 OCTOBER 1987 REVISION LEVEL A 67268 5962-87541 | D | RAW | /IN | G | | | ADI | PROV | P.B | | | | | • | T | HREE | -0U | TPUT | OR | GAT | Ε, Ν | 10NO | ĹĬŤ | ΗIC | SIL | COŃ | |
| FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE 22 OCTOBER 1987 REVISION LEVEL A 67268 5962-87541 | | | | | | | DE | WIN | G AD | PROV | | Ĵ | 1 | | ╁ | SIZE | Т | | AGE | ~~~ | | Т | | | | | \dashv |
| DEPARTMENT OF DEFENSE REVISION LEVEL | FOR USE | BY ALL | DEP | ARTI | MEN | | | | | | , | | | | İ | _ | l | | | | | | 59 | 962-87541 | | | |
| AMSC N/A SHEET 1 OF 13 | DEPAR | TMENT | OF C | EFE | NSE | ľ | | | | _ | | | | | 1 | | | | - | | | | | | _ | | |
| | AMSC | N/A | | | | | | | | | | A | | | | | SHE | ET | | 1 | | OF | | 13 | | | |

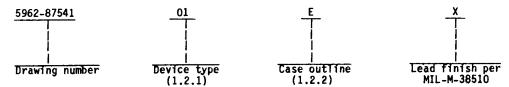
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5962-E1103

| SCOP |
|------|
| |
| |

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with $1.\overline{2.1}$ of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:



1.2.1 Device type. The device type shall identify the circuit function as follows:

| Device type | Generic number | Circuit function | | | | | | |
|-------------|----------------|--|--|--|--|--|--|--|
| 01 | 10H610 | Dual three-input, three-output OR gate | | | | | | |

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

```
        Outline letter
        Case outline

        E
        D-2 (16-lead, .840" x .310" x .200"), dual-in-line package

        F
        F-5 (16-lead, .440" x .285" x .085"), flat package

        2
        C-2 (20-terminal, .358" x .358" x .100"), square chip carrier package
```

1.3 Absolute maximum ratings.

1.4 Recommended operating conditions.

| Supply voltage range (VEE) | -5.46 V dc minimum to -4.94 V dc maximum |
|--|--|
| Supply voltage range (V_{CC}) | -0.02 V dc to +0.02 V dc or 1.98 V dc |
| | to 2.02 V dc |
| Ambient operating temperature range (TA) | -55°C to +125°C |
| Minimum high level input voltage (V _{IH}): | |
| TA = +25°C | -0.780 V dc |
| T _A = +25°C | -0.650 Y dc |
| TA = -55°C | -0.840 V dc |
| Maximum low level input voltage (V_{IL}) | -1.950 V dc |

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444 SIZE A 5962-87541 REVISION LEVEL SHEET A 2

2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510

- Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883

Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

- $3.1\,$ Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
 - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
 - 3.2.2 Truth table. The truth table shall be as specified on figure 2.
 - 3.2.3 Logic diagrams. The logic diagrams shall be as specified on figure 3.
- 3.2.4 Test circuit and switching waveforms. The test circuit and switching waveforms shall be as specified on figure 4.
 - 3.2.5 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full ambient operating temperature range.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.
- 3.5 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

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| Test | Symbol | i -55°C | Conditi < TA < | +125°C | 61 0 4 | Group A | Limi Min | ts Max | Unit | | | | |
|-------------------------------------|-----------------------|--|---------------------------------------|------------------------------|-----------------------|-----------|---------------------------------------|------------|--|---|-----------------------------------|--------|---|
| Cases E, F, and 2 | <u> </u> | | | se specions | | | MIN 1 | riax | | | | | |
| High level output voltage | I I I I I | Outputs terminated through 1000 to -2 | terminated | | terminated through | | terminated -0.780 through -0.650 | | V _{IL} -1.950 -1.950 | 2 | -1.010 -0.860 -1.060 | -0.650 | 1 |
| Low level output voltage | i v _{ol} | V _{CC} = 0.0 V V _{EE} = -5.2 | | -0.780 -0.650 -0.840 | -1.950 | • | -1.950 -1.950 -1.950 | -1.565 | Į | | | | |
| High level threshold output voltage | VOHA | - - | | -1.110 -0.960 -1.160 | 1-1.465 | 2 | -1.010 -0.860 -1.060 | -0.650 | ļ | | | | |
| Low level threshold output voltage | VOLA | | | -1.110 -0.960 -1.160 | -1.465 | | -1.950 -1.950 -1.950 | -1.565 | 1 | | | | |
| Power supply drain 3/ | IEE | V _{EE} = -5.46 V _{IH} = -0.78 | 0 at +2 | £5°C | v | 1 2, 3 | -38 -42 | | mA | | | | |
| High level input current | IIH | -0.65 -0.84 | -0.650 at +125°C -0.840 at -55°C | | | | | 450 720 | μΑ | | | | |
| Low level input current | IIL | VEE = -4.94 VIL = -1.95 VCC = 0.0 \ | 0 V | <u>3</u> / | | 1, 3 | 0.5 0.3 | | μ Α | | | | |
| Functional tests | | See 4.3.1c | | | | 7,8 |] | i i | | | | | |
| See footnotes at end of ta | ble. | | | | | | | | | | | | |
| STANDARDIZE MILITARY DRAW | | SIZE A | T | | | 59 | 62-8754 | 1 | | | | | |
| | | | | | | | | | | | | | |

| Test | Symbol | Condi -55°C < T _A | < +125°C | | Group A subgroups | | | l Uni |
|-------------------------------------|-----------------------------|---|------------------------------|--|----------------------------|------------------------------|------------|----------------|
| Cases E and F | <u> </u> | unless other DC rapid tes | | 1 | Min | Max | <u>!</u> | |
| | 1 | | | V | Ţ | | I | <u> </u> |
| High level output voltage | i I V _{OH} I | Outputs terminated through 1000 to -2 Y | | V _{IL} -1.950 -1.950 -1.950 | 1 1 2 1 3 | -1.021 -0.872 -1.072 | -0.663 | į |
| Low level output voltage | V _{OL} | V _{CC} = 0.0 V V _{EE} = -5.2 V <u>2</u> / | | -1.950 -1.950 -1.950 | 1 2 3 | -1.950 -1.950 -1.950 | | ! |
| High level threshold output voltage | I V _{OHA} | _ | -1.121 -0.972 -1.172 | -1.469 | 1 2 3 | -1.021 -0.872 -1.072 | -0.663 | 1 |
| Low level threshold output voltage | VOLA | | -1.121 -0.972 -1.172 | -1.469 | j 2 | -1.950 -1.950 -1.950 | -1.569 | 1 |
| Power supply drain 3/ | IEE | $V_{EE} = -5.46 \text{ V},$ $V_{IH} = -0.792 \text{ at}$ | +25°C | V | 2, 3 | -37 -41 | | m |
| High level input current | IIH | -0.663 at -0.853 at | +125 C -55 C | | 1, 2 | | 435 705 | ļ μ |
| Low level input current | IIL | VEE = -4.94 V, VIL = -1.950 V | V _{CC} = 0.0 | ۷ <u>3</u> / | 1,3 | 0.5 | | μ |
| Functional tests | | See 4.3.1c | | | 7, 8 | | | |
| See footnotes at end of ta | ble. | | | | | | | |
| | | | | | · | | | |
| STANDARDIZE MILITARY DRAW | _ | SIZE A | | T | | 062-8754 | 1 | |

| Test | Symbol | i Condit | ions | | Group A | Limi | Unit | |
|-------------------------------------|---|---|------------------------------|------------------------------|------------------|-----------------------------------|------------------------------|-----------|
| | -55°C < T _A < +125°C unless otherwise specified | | | | subgroups | Min | Max | <u> </u> |
| Case 2 | | DC rapid test | condition | s <u>4</u> / | | | | |
| | | | NIH NIH | VIL | | | | |
| High level output voltage | VOH | Outputs terminated through 100Ω to -2 V | -0.800 -0.671 -0.861 | 1-1.950 | | -1.028 -0.880 -1.080 | | Ì |
| Low level output voltage | VOL | V _{CC} = 0.0 V V _{EE} = -5.2 V 2/ | 1-0.671 | -1.950 -1.950 -1.950 | 1 2 3 | | -1.586 -1.572 -1.657 | ĺ |
| High level threshold output voltage | VOHA | | 1-0.980 | -1.486 -1.472 -1.557 | 1 2 3 | -0.880 | -0.800 -0.671 -0.861 | Ì |
| Low level threshold output voltage | V _{OLA} | | | -1.486 -1.472 -1.557 | 1 2 3 | -1.950 | -1.586 -1.572 -1.657 | Ì |
| Power supply drain 3/ current | IEE | V _{EE} = -5.46 V, V V _{IH} = -0.800 at + | 25°Ç | ٧ | 1 2,3 | -37 -41 | | m/ |
| High level input current | IIH | -0.671 at + -0.861 at - | | | 1, 2 | ! | 435 705 | μA |
| Low level input current | IIL | VEE = -4.94 V, V VIL = -1.950 V | $\frac{3}{2}$ | ٧ | 1,3 | 0.5 0.3 | | |
| Functional tests | | See 4.3.1c | | | 7,8 |] |] | |

See footnotes at end of table.

| STANDARDIZED MILITARY DRAWING | SIZE A | | |
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| DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444 | | REVISION LEVE | - |

6

5962-87541 SHEET

| Test | Symbol | Conditions | Group A | Lim | Unit | |
|--------------------------------------|------------------|--|---------------------|----------------------|--------------------------|--------|
| | | -55°C < T _A < +125°C unless otherwise specified | subgroups | Min | Max | |
| Cases E, F, and 2 | | AC test conditions | | | | |
| Transition time | tTLH tTHL | V _{EE} = -2.94 V V _{CC} = 2.0 V C ₁ < 5 pF ±10% | 9 10 11 | 0.50 0.50 0.50 | 1.80 1.90 1.75 | ns |
| Propagation delay time, A, B to Y | t _{PLH} | Lōad all outputs through 100Ω to ground See figure 4 | 9 10 11 | 0.40 0.40 0.40 | 1.65 1.90 1.85 | ns |
| | tpHL | - - | 9 10 11 | 0.40 0.40 0.40 | 1.70 1.95 1.60 | ns |

- 1/ The quiescent limits are determined after a device has reached thermal equilibrium. This is defined as the reading taken with the device in a socket with > 500 LFPM of +25°C, +125°C or -55°C (as applicable) air blowing on the unit in a transverse direction with power applied for at least 4 minutes before the reading is taken. This method was used for theoretical limit establishment only. All devices shall be tested to the delta V (rapid test) conditions specified herein. The rapid test method is an equivalent method of testing quiescent conditions.
- 2/ The high and low level output current varies with temperature, and shall be calculated using the following formulas:

 $\begin{array}{l} I_{OH} = (V_{OH} - 2 \ V)/100\Omega \\ I_{OL} = (V_{OL} - 2 \ V)/100\Omega \end{array}$

- $\underline{3/}$ The $I_{\mbox{\scriptsize FE}}$ and $I_{\mbox{\scriptsize IL}}$ limits, although specified in the minimum column, shall not be exceeded in magnitude as a maximum value.
- 4/ The dc rapid test forcing functions and limits are used for all dc testing. These limits are determined for each device type based on the power dissipation and package type. The rapid test (delta V) limits and forcing functions are skewed allowing rapid testing to be performed at standard temperatures without the addition of delta T's.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

| STANDARDIZED MILITARY DRAWING | SIZE A | | 5962-87541 | |
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| DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444 | | REVISION LEVEL | SHEET 7 | |

| Case outlines | l E | F | 2 | | | |
|---|---|---|---|--|--|--|
| Terminal number | Terminal symbol | | | | | |
| 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20 | VCC1 Y1 Y2 Y2 A1 A2 A3 VEE B1 B2 B3 Y4 Y5 NC VCC2 | Y5 Y6 NC VCC2 VCC1 Y1 Y2 Y3 A1 A2 A3 VEE B1 B2 B3 | NC VCC1 Y1 Y2 Y3 NC A1 A2 A2 B1 B2 B3 Y4 Y5 NC Y6 Y6 VCC2 | | | |

NC = No connection

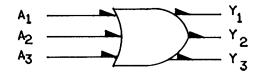
FIGURE 1. Terminal connections.

| STANDARDIZED MILITARY DRAWING | SIZE A | 5962-87541 | | 541 | | |
|--|-----------|------------|----------------|--------|---------|--|
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| Inputs | | | Outputs | | | |
|--------------------------------|-------|-------------|--------------------------------|-------|-------|--|
| A ₁ /B ₁ | A2/B2 | A3/B3 | Y ₁ /Y ₄ | Y2/Y5 | Y3/Y6 | |
| L | L | L | L | L | L | |
| L | L | н | Н | н | Н | |
| <u> </u> | Н | L | Н | н | Н | |
| L | н | н | Н | н | Н | |
| н | L | L | Н | Н | Н | |
|) H | L | н | н | н | н | |
|) H | Н | L | н | н | н | |
| H | н | H | H | Н | Н | |

FIGURE 2. Truth table.



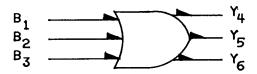


FIGURE 3. Logic diagrams.

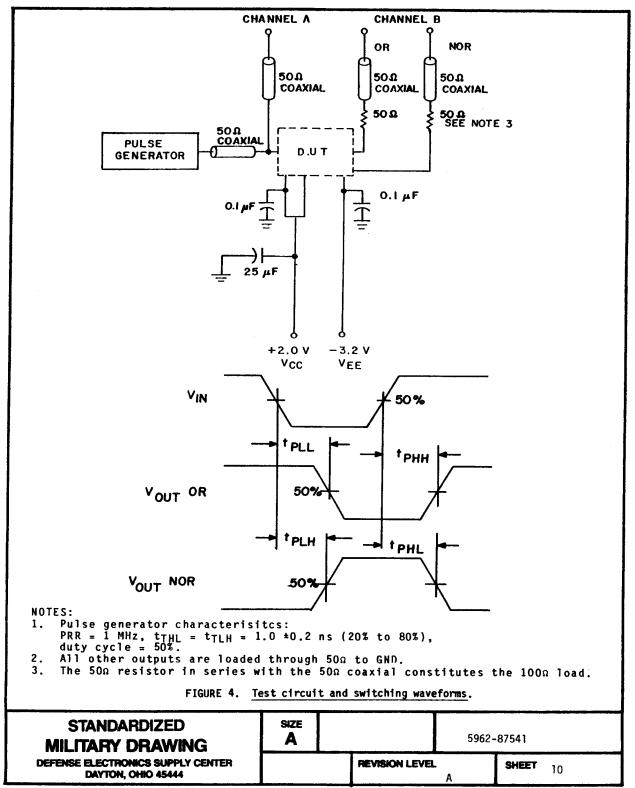
STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SURRI Y CENTER

DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444

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4. QUALITY ASSURANCE PROVISIONS

- 4.1 <u>Sampling and inspection</u>. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test, method 1015 of MIL-STD-883.
 - Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 4, 5, and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
 - c. Subgroups 7 and 8 tests shall verify the truth table as specified on figure 2.
 - 4.3.2 Groups C and D inspections.
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

| STANDARDIZED MILITARY DRAWING | SIZE A | | 5 | 962-87541 | |
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| DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444 | | REVISION LEVEL | A | SHEET | 11 |

TABLE II. <u>Electrical</u> test requirements.

| MIL-STD-883 test requirements | Subgroups (per method 5005, table I) |
|--|--|
| Interim electrical parameters (method 5004) | 1 |
| Final electrical test parameters (method 5004) | 1*, 2, 3, 7*, 8, 9 |
| Group A test requirements (method 5005) | 1, 2, 3, 7, 8, 9, 10, 11 |
| Groups C and D end-point electrical parameters (method 5005) | 1, 2, 3 |

^{*} PDA applies to subgroups 1 and 7.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
- 6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

| STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444 | SIZE A | | | 5962-87541 | |
|--|-----------|----------------|---|------------|--|
| | | REVISION LEVEL | A | SHEET 12 | |

6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

| Military drawing part number | Vendor CAGE number | Vendor similar part number <u>1</u> / |
|---------------------------------|----------------------------------|---|
| 5962-8754101EX | 04713 | 10H610/BEAJC |
| 5962-8754101FX | 04713 | 10H61O/BFAJC |
| 5962-87541012X | 04713 | 10H610M/B2AJC |

Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

04713

Vendor name and address

Motorola, Incorporated 7402 South Price Road Tempe, AZ 85283

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|-------------------------|--|
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